Approved by:

Checked by:

Issued by:

# **SPECIFICATION**

MODEL: HDF434M(TO39)



SHOULDER ELECTRONIC LIMITED

# 1.SCOPE

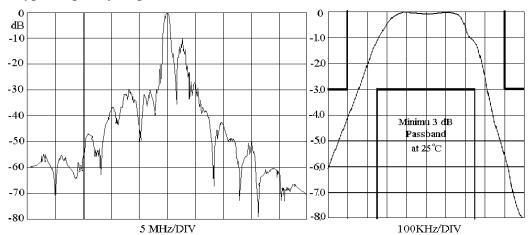
This specification shall cover the characteristics of SAW filter with used for remote-control security.

# 2. ELECTRICAL SPECIFICATION

DC Voltage VDC	10V
AC Voltage Vpp	10V50Hz/60Hz
Storage temperature	-45°C to +85°C
RF Power Dissipation	0dBm

#### **Electronic Characteristics**

## 2-1. Type frequency response

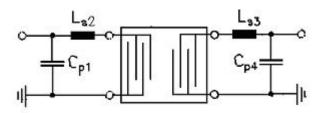


## 2-2. Electrical characteristics

Characteristics			Sym	Notes	Min.	Typical	Max.	Units
Center	Absolute Frequency		Fc	1.2	433.94	434.02	434.10	M Hz
Frequency	tolerance from Nominal		Δ fc			500	700	KHz
Insertion Loss			IL	1		1.7	3.0	dB
3dB Bandwidth			BW <sub>3</sub>	1.2	500	700	800	KHz
Rejection	At fo-21.4MHz (Image)			1	40	50		dB
	At fo-10.7 MHz (LO)				16	40		
	Ult	Ultimate				80		
Temperature Operating case temp.		Tc	3.4	-35		+85	$^{\circ}$	
characteristics '		Tumover temp.	То		22	37	62	$^{\circ}$
		Tumover Frequency	fo			fc		MHz
Freq.te		Freq.temp.coefficient	FTC			0.032		ppm/℃
Frequency aging			5		<±10		ppm/y	

## 3. Matching network to $50 \Omega$ (element values depend on pcb

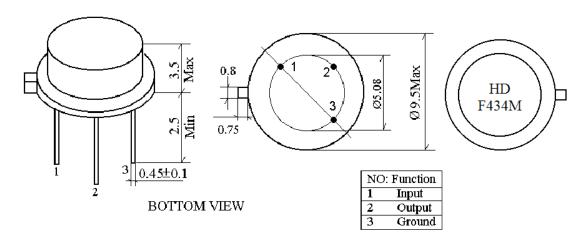
layout and equivalent circuit)



Cp1 =10pF, Ls2 =43nH\*, Ls3 =43nH\*, Cp4 =10pF

Ls2 = Ls3 = 6 turns of 0.51mm insulated Copper, 2.5mm ID.

## 4. DIMENSION



## 5. ENVIRONMENTAL CHARACTERISTICS

#### 5-1 High temperature exposure

Subject the device to  $+85^{\circ}$ C for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in table 1.

#### 5-2 Low temperature exposure

Subject the device to  $-20^{\circ}$ C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in table 1.

#### 5-3 Temperature cycling

Subject the device to a low temperature of -40°C for 30 minutes. Following by a high temperature of +80°C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in table 1.

#### 5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at  $260^{\circ}$ C  $\pm 10^{\circ}$ C for  $10\pm 1$  sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in table 1.

#### 5-5 Solderability

Subject the device terminals into the solder bath at  $245^{\circ}$ C  $\pm 5^{\circ}$ C for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in table 1.

#### 5-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in table 1.

#### 5-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in table 1.

### 5-8 Lead fatigue

## 5-8-1 Pulling test

Weight along with the direction of lead without an shock 1kg. The device shall satisfy all the initial Characteristics.

## 5-8-2 Bending test

Lead shall be subject to withstand against 90°C bending with 450g weight in the direction of thickness. This operation shall be done toward both direction. The device shall show no evidence of damage and shall satisfy all the initial electrical characteristics.

#### 6. REMARK

#### 6.1 Static voltage

Static voltage between signal load & ground may cause deterioration & destruction of the component. Please avoid static voltage.

#### 6.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

#### 6.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.